
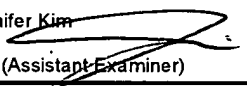
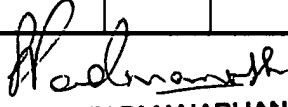
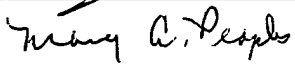


<b>Issue Classification</b>  	Application/Control No.	Applicant(s)/Patent under Reexamination
	10075718	CHEN, ALLAN Y.
	Examiner:  Kim, Jennifer	Art Unit:  1617

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS	SUBCLASS				CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
514	43				514	410	416		
INTERNATIONAL CLASSIFICATION									
A	6	1	K	31170					
A	6	1	K	31140					
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				/					
				/					
Jennifer Kim  (Assistant Examiner) 5/10/05 (Date)					 <b>SREENI PADMANABHAN</b> <b>SUPERVISORY PATENT EXAMINER</b> (Primary Examiner) 5/15/05 (Date)				
 (Legal Instrument Examiner) 5/16/05 (Date)					Total Claims Allowed: 6 . Print Claim(s) 1 O.G. Print Flg. 0				

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